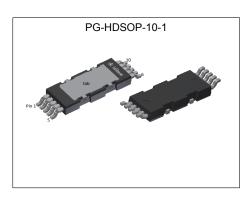


## **MOSFET**

#### 600V CoolMOS™ CFD7 Power Transistor

CoolMOS<sup>TM</sup> is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies. The latest CoolMOS<sup>TM</sup> CFD7 is the successor to the CoolMOS<sup>TM</sup> CFD2 series and is an optimized platform tailored to target soft switching applications such as phase-shift full-bridge (ZVS) and LLC. Resulting from reduced gate charge (Qg), best-in-class reverse recovery charge (Qr) and improved turn off behavior CoolMOS<sup>TM</sup> CFD7 offers highest efficiency in resonant topologies. As part of Infineon's fast body diode portfolio, this new product series blends all advantages of a fast switching technology together with superior hard commutation robustness, without sacrificing easy implementation in the design-in process.



# Gate Pin 1 Driver Source Pin 2 Power Source Pin 3,4,5







#### **Features**

- Ultra-fast body diode
- Low gate charge
- Best-in-class reverse recovery charge (Q<sub>rr</sub>)
- Improved MOSFET reverse diode dv/dt and di<sub>F</sub>/dt ruggedness
- Lowest FOM R<sub>DS(on)</sub>\*Q<sub>g</sub> and R<sub>DS(on)</sub>\*E<sub>oss</sub>
- Best-in-class R<sub>DS(on)</sub> in SMD and THD packages

#### **Benefits**

- Excellent hard commutation ruggedness
- Highest reliability for resonant topologies
- Highest efficiency with outstanding ease-of-use / performance tradeoff
- Enabling increased power density solutions

### Potential applications

Suitable for Soft Switching topologies Optimized for phase-shift full-bridge (ZVS), LLC Applications – Server, Telecom, EV Charging

#### Product validation

Fully qualified according to JEDEC for Industrial Applications

Please note: The source and sense source pins are not exchangeable. Their exchange might lead to malfunction. For paralleling 4pin MOSFET devices the placement of the gate resistor is generally recommended to be on the Driver Source instead of the Gate.

Table 1 Key Performance Parameters

Table 1 Rey Ferformance Farameters						
Parameter	Value	Unit				
V <sub>DS</sub> @ T <sub>j,max</sub>	650	V				
R <sub>DS(on),max</sub>	45	mΩ				
$Q_{g,typ}$	79	nC				
I <sub>D,pulse</sub>	153	A				
E <sub>oss</sub> @ 400V	9.1	μJ				
Body diode di <sub>F</sub> /dt	1300	A/µs				

Type / Ordering Code	Package	Marking	Related Links
IPDD60R045CFD7	PG-HDSOP-10	60R045F7	see Appendix A



# **Table of Contents**

Description
Maximum ratings 3
Thermal characteristics
Electrical characteristics 5
Electrical characteristics diagrams
Test Circuits
Package Outlines
Appendix A
Revision History
Trademarks
Disclaimer



1 Maximum ratings at  $T_j = 25$ °C, unless otherwise specified

Table 2 Maximum ratings

Davamatar	Values						
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous drain current <sup>1)</sup>	I <sub>D</sub>	-	-	61 39	А	T <sub>C</sub> =25°C T <sub>C</sub> =100°C	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	-	-	153	Α	T <sub>C</sub> =25°C	
Avalanche energy, single pulse	<b>E</b> AS	-	-	180	mJ	I <sub>D</sub> =6.5A; V <sub>DD</sub> =50V; see table 10	
Avalanche energy, repetitive	<b>E</b> AR	-	-	0.90	mJ	I <sub>D</sub> =6.5A; V <sub>DD</sub> =50V; see table 10	
Avalanche current, single pulse	I <sub>AS</sub>	-	-	6.5	Α	-	
MOSFET dv/dt ruggedness	dv/dt	-	-	120	V/ns	V <sub>DS</sub> =0400V	
Gate source voltage (static)	V <sub>GS</sub>	-20	-	20	V	static;	
Gate source voltage (dynamic)	V <sub>GS</sub>	-30	-	30	V	AC (f>1 Hz)	
Power dissipation	P <sub>tot</sub>	-	-	379	W	<i>T</i> <sub>C</sub> =25°C	
Storage temperature	$T_{ m stg}$	-55	-	150	°C	-	
Operating junction temperature	T <sub>j</sub>	-55	-	150	°C	-	
Mounting torque	-	-	-	n.a.	Ncm	-	
Continuous diode forward current <sup>1)</sup>	Is	-	-	61	Α	<i>T</i> <sub>C</sub> =25°C	
Diode pulse current <sup>2)</sup>	I <sub>S,pulse</sub>	-	-	153	Α	<i>T</i> <sub>C</sub> =25°C	
Reverse diode dv/dt <sup>3)</sup>	dv/dt	-	-	70	V/ns	$V_{\rm DS}$ =0400V, $I_{\rm SD}$ <=38A, $T_{\rm j}$ =25°C see table 8	
Maximum diode commutation speed	di <sub>F</sub> /dt	-	-	1300	A/μs	V <sub>DS</sub> =0400V, I <sub>SD</sub> <=38A, T <sub>j</sub> =25°C see table 8	
Insulation withstand voltage	V <sub>ISO</sub>	-	-	n.a.	V	V <sub>rms</sub> , T <sub>C</sub> =25°C, t=1min	

 $<sup>^{1)}</sup>$  Limited by  $T_{j\,\text{max}}.$   $^{2)}$  Pulse width  $t_p$  limited by  $T_{j,\text{max}}$   $^{3)}$  Identical low side and high side switch with identical  $R_G$ 



# 2 Thermal characteristics

## Table 3 Thermal characteristics

Davamatav	Cumbal	Values			11	Note / Took Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	0.33	°C/W	-
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	62	°C/W	device on PCB, minimal footprint
Thermal resistance, junction - ambient for SMD version	<b>N</b> thJA	-	55	60	°C/W	Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70µm thickness) copper area. Tap exposed to air. PCB is vertical without air stream cooling.
Soldering temperature, reflow soldering allowed	T <sub>sold</sub>	_	-	260	°C	reflow MSL1



### **Electrical characteristics**

at T<sub>j</sub>=25°C, unless otherwise specified

Table 4 **Static characteristics** 

Parameter	Oh o.l		Values			Nata / Tank Oam distant
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	600	-	-	V	$V_{GS}$ =0V, $I_D$ =1mA
Gate threshold voltage	V <sub>(GS)th</sub>	3.5	4	4.5	V	$V_{\rm DS}=V_{\rm GS},\ I_{\rm D}=0.9{\rm mA}$
Zero gate voltage drain current <sup>1)</sup>	I <sub>DSS</sub>	-	- 19	1 75	μΑ	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V, T <sub>j</sub> =25°C V <sub>DS</sub> =600V, V <sub>GS</sub> =0V, T <sub>j</sub> =125°C
Gate-source leakage current	I <sub>GSS</sub>	-	-	100	nA	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	0.038 0.087	0.045	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =18.0A, T <sub>j</sub> =25°C V <sub>GS</sub> =10V, I <sub>D</sub> =18.0A, T <sub>j</sub> =150°C
Gate resistance	<b>R</b> <sub>G</sub>	-	5.8	-	Ω	f=1MHz, open drain

Table 5 **Dynamic characteristics** 

Parameter	Oh al	Values				
	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance	Ciss	-	3194	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V, f=250kHz
Output capacitance	Coss	-	62	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =400V, f=250kHz
Effective output capacitance, energy related <sup>2)</sup>	C <sub>o(er)</sub>	-	114	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0400V
Effective output capacitance, time related <sup>3)</sup>	C <sub>o(tr)</sub>	-	1166	-	pF	I <sub>D</sub> =constant, V <sub>GS</sub> =0V, V <sub>DS</sub> =0400V
Turn-on delay time	$t_{\sf d(on)}$	-	27	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =10V, $I_{\rm D}$ =13.7A, $R_{\rm G}$ =3.0 $\Omega$ ; see table 9
Rise time	t <sub>r</sub>	-	19	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =10V, $I_{\rm D}$ =13.7A, $R_{\rm G}$ =3.0 $\Omega$ ; see table 9
Turn-off delay time	$t_{ m d(off)}$	-	101	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =10V, $I_{\rm D}$ =13.7A, $R_{\rm G}$ =3.0 $\Omega$ ; see table 9
Fall time	t <sub>f</sub>	-	5	-	ns	$V_{\rm DD}$ =400V, $V_{\rm GS}$ =10V, $I_{\rm D}$ =13.7A, $R_{\rm G}$ =3.0 $\Omega$ ; see table 9

Table 6 **Gate charge characteristics** 

Davamatav	Symbol	Values			Unit	Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Gate to source charge	Q <sub>gs</sub>	-	18	-	nC	$V_{DD}$ =400V, $I_{D}$ =13.7A, $V_{GS}$ =0 to 10V
Gate to drain charge	$Q_{ m gd}$	-	29	-	nC	$V_{DD}$ =400V, $I_{D}$ =13.7A, $V_{GS}$ =0 to 10V
Gate charge total	$Q_g$	-	79	-	nC	$V_{DD}$ =400V, $I_{D}$ =13.7A, $V_{GS}$ =0 to 10V
Gate plateau voltage	V <sub>plateau</sub>	-	5.5	-	V	$V_{DD}$ =400V, $I_{D}$ =13.7A, $V_{GS}$ =0 to 10V

 $<sup>^{1)}</sup>$  Maximum specification is defined by calculated six sigma upper confidence bound  $^{2)}$   $C_{\rm o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 400V  $^{3)}$   $C_{\rm o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 400V

# 600V CoolMOS™ CFD7 Power Transistor

IPDD60R045CFD7

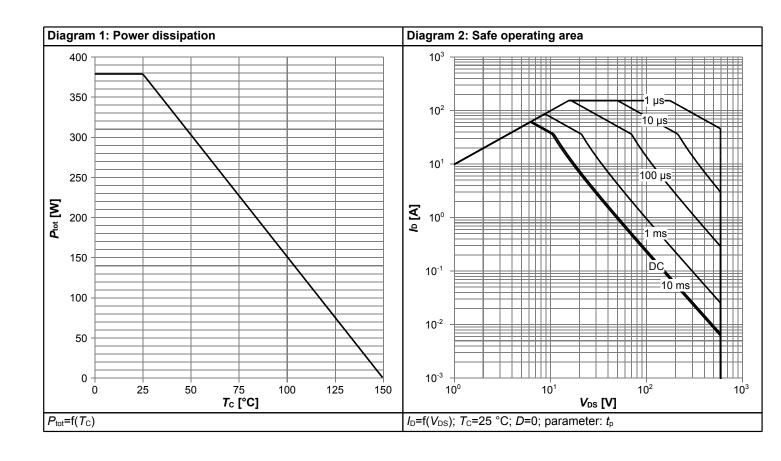


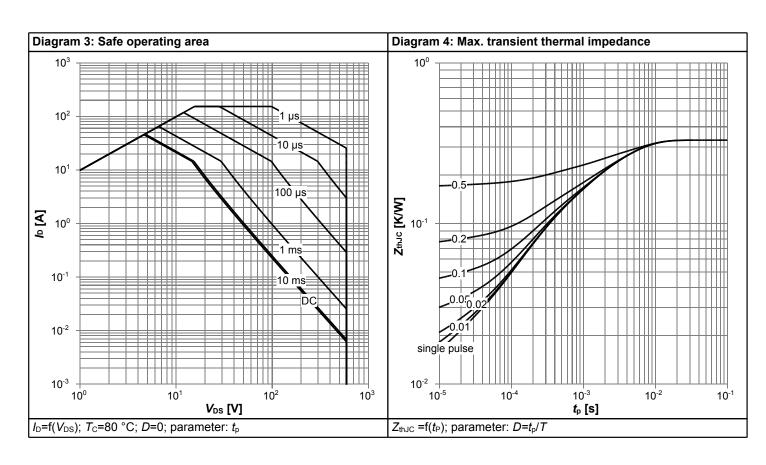
# Table 7 Reverse diode characteristics

Parameter	Symbol	Values			11	Nata / Tant Can dition
		Min.	Тур.	Max.	Unit	Note / Test Condition
Diode forward voltage	V <sub>SD</sub>	-	1.0	-	V	V <sub>GS</sub> =0V, I <sub>F</sub> =18.0A, T <sub>j</sub> =25°C
Reverse recovery time	t <sub>rr</sub>	-	132	198	ns	$V_R$ =400V, $I_F$ =13.7A, $di_F/dt$ =100A/ $\mu$ s; see table 8
Reverse recovery charge	Q <sub>rr</sub>	-	0.68	1.37	μC	$V_R$ =400V, $I_F$ =13.7A, $di_F/dt$ =100A/ $\mu$ s; see table 8
Peak reverse recovery current	I <sub>rrm</sub>	-	8.8	-	А	$V_R$ =400V, $I_F$ =13.7A, $di_F/dt$ =100A/ $\mu$ s; see table 8

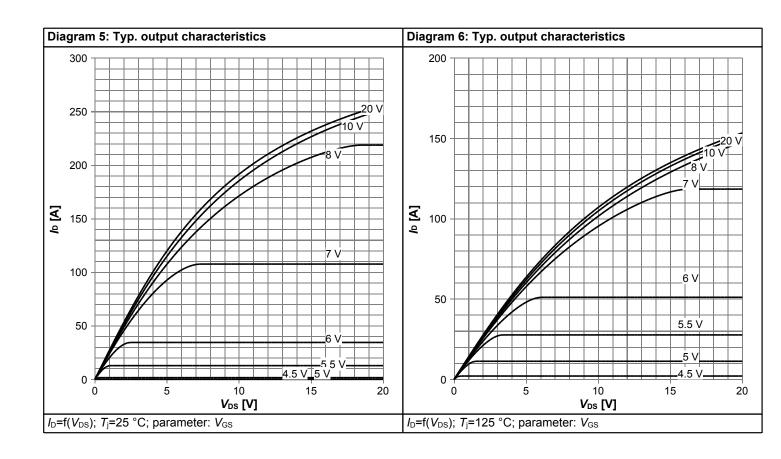


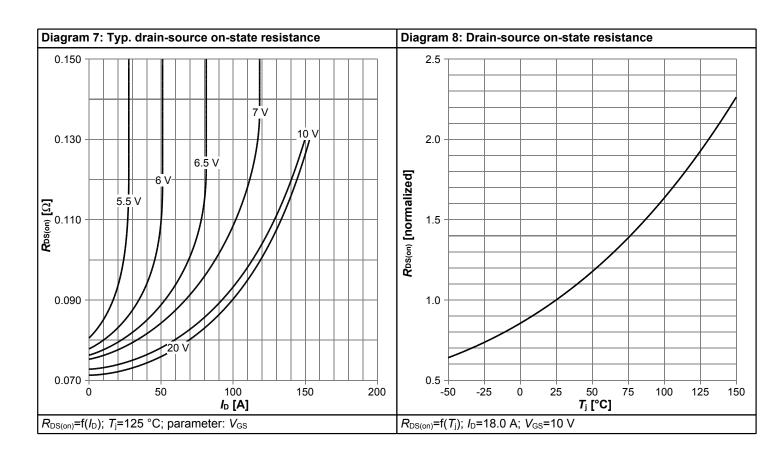
# 4 Electrical characteristics diagrams



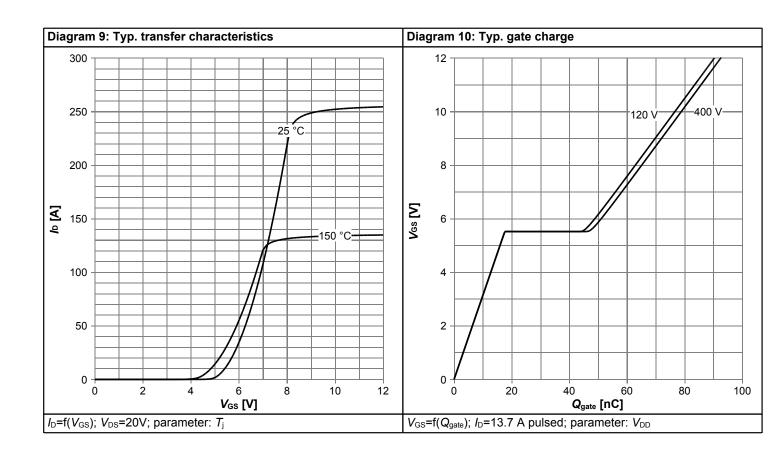


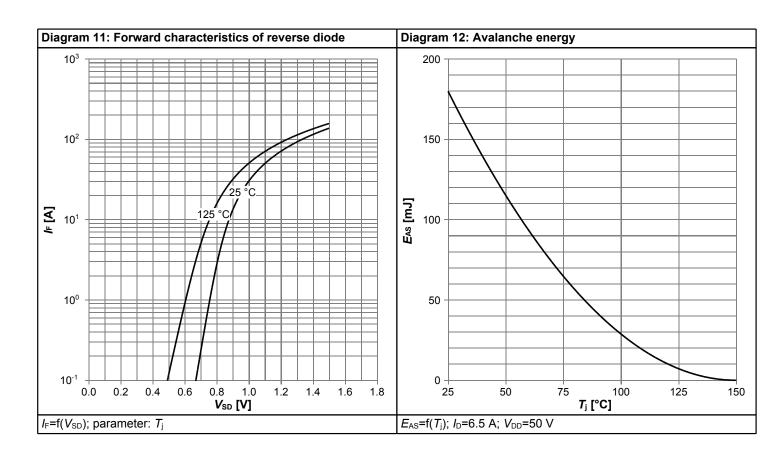




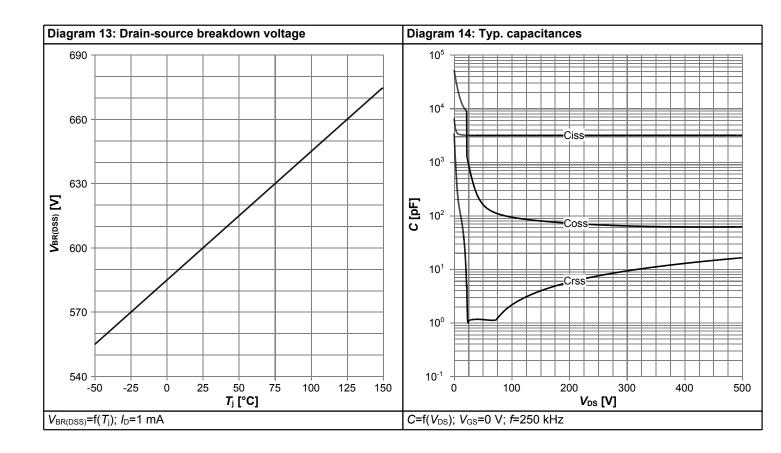


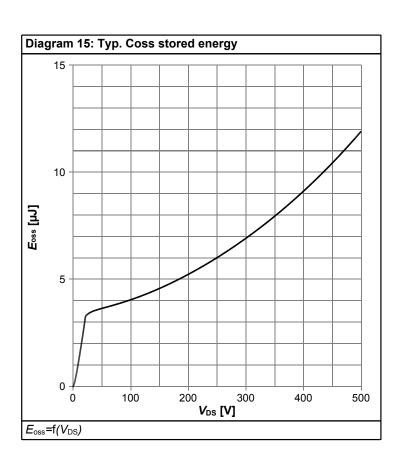














### 5 Test Circuits

**Table 8** Diode characteristics

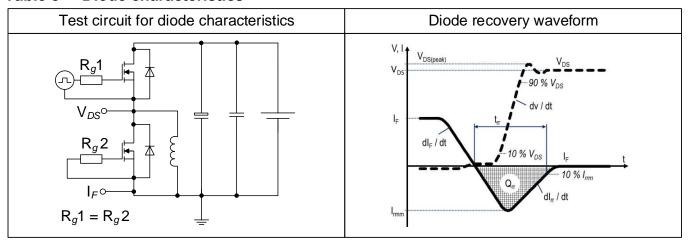
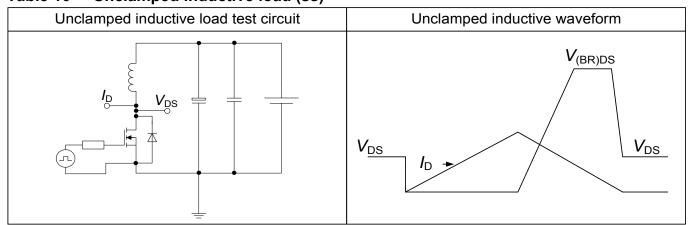


Table 9 Switching times (ss)



Table 10 Unclamped inductive load (ss)





# 6 Package Outlines

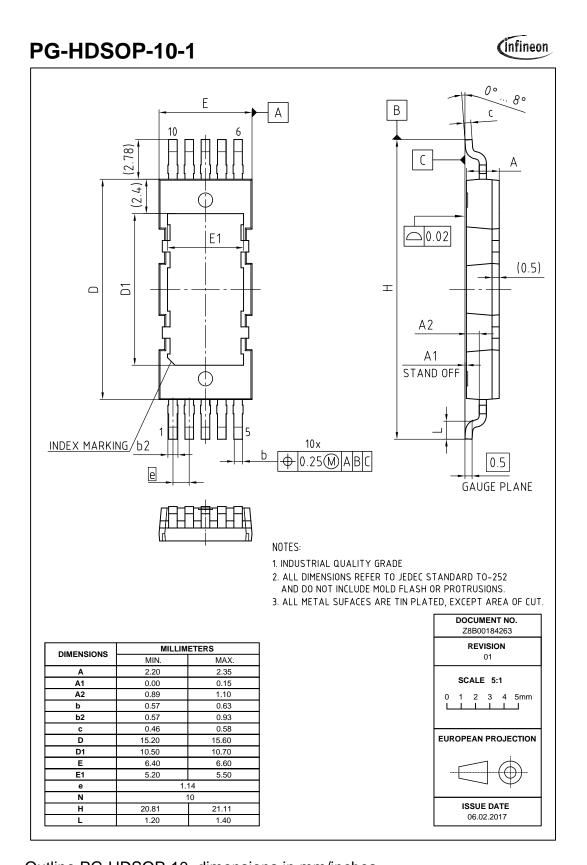


Figure 1 Outline PG-HDSOP-10, dimensions in mm/inches



# 7 Appendix A

#### Table 11 Related Links

• IFX CoolMOS CFD7 Webpage: www.infineon.com

• IFX CoolMOS CFD7 application note: <u>www.infineon.com</u>

• IFX CoolMOS CFD7 simulation model: <u>www.infineon.com</u>

• IFX Design tools: <u>www.infineon.com</u>



#### Revision History

IPDD60R045CFD7

Revision: 2020-09-16, Rev. 2.0

#### **Previous Revision**

Revision	Date	Subjects (major changes since last revision)
2.0	2020-09-16	Release of final version

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Final Data Sheet 14 Rev. 2.0, 2020-09-16